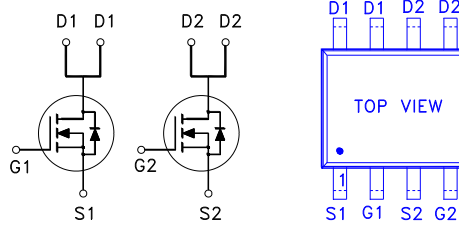


PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	55mΩ	4A



G: GATE
D: DRAIN
S: SOURCE

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		V_{DS}	60	V
Gate-Source Voltage		V_{GS}	±20	V
Continuous Drain Current	$T_A = 25^\circ\text{C}$	I_D	4	A
	$T_A = 70^\circ\text{C}$		3.2	
Pulsed Drain Current ¹		I_{DM}	16	
Avalanche Current		I_{AS}	14.5	
Avalanche Energy	$L = 0.1\text{mH}$	E_{AS}	10.6	mJ
Power Dissipation ³	$T_A = 25^\circ\text{C}$	P_D	2	W
	$T_A = 70^\circ\text{C}$		1.28	
Junction & Storage Temperature Range		T_J, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$t \leq 10\text{s}$	$R_{\theta JA}$		62.5	°C / W
Junction-to-Ambient	Steady-State	$R_{\theta JA}$		110	
Junction-to-Case	Steady-State	$R_{\theta JC}$		60	

¹Pulse width limited by maximum junction temperature.

²The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$.

³The Power dissipation is based on $R_{\theta JA} t \leq 10\text{s}$ value.

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

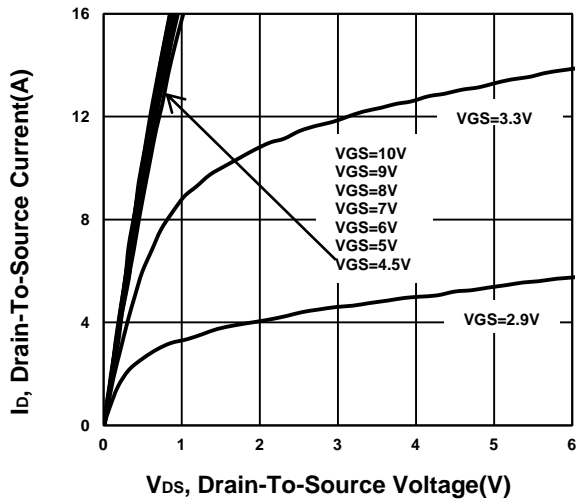
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.3	1.75	2.3	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			±100	nA

Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 60V, V_{GS} = 0V$			1	μA	
		$V_{DS} = 48V, V_{GS} = 0V, T_J = 55^\circ C$			10		
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 4.5V, I_D = 3A$		50	72	$m\Omega$	
		$V_{GS} = 10V, I_D = 3A$		42	55		
Forward Transconductance ¹	g_{fs}	$V_{DS} = 5V, I_D = 3A$		13		S	
DYNAMIC							
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		308	385	462	pF
Output Capacitance	C_{oss}			44	55	66	
Reverse Transfer Capacitance	C_{rss}			23	39	55	
Gate Resistance	R_g	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		1	2	3	Ω
Total Gate Charge ²	$Q_{g(VGS=10V)}$	$V_{DS} = 30V, I_D = 3A$		8.8	11	13.2	nC
	$Q_{g(VGS=4.5V)}$			5	6.3	7.6	
Gate-Source Charge ²	Q_{gs}			1	1.2	1.4	
Gate-Drain Charge ²	Q_{gd}			2.3	3.9	5.5	
Turn-On Delay Time ²	$t_{d(on)}$		$V_{DS} = 30V, I_D \cong 3A, V_{GS} = 10V, R_{GEN} = 6\Omega$			9.9	
Rise Time ²	t_r				16		
Turn-Off Delay Time ²	$t_{d(off)}$				23		
Fall Time ²	t_f				12		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ C$)							
Continuous Current	I_S				0.9	A	
Forward Voltage ¹	V_{SD}	$I_F = 3A, V_{GS} = 0V$			1.2	V	
Diode Reverse Recovery Time	t_{rr}	$I_F = 3A, dI/dt = 100A/\mu s$		8	16	24	nS
Diode Reverse Recovery Charge	Q_{rr}			3	6	9	nC

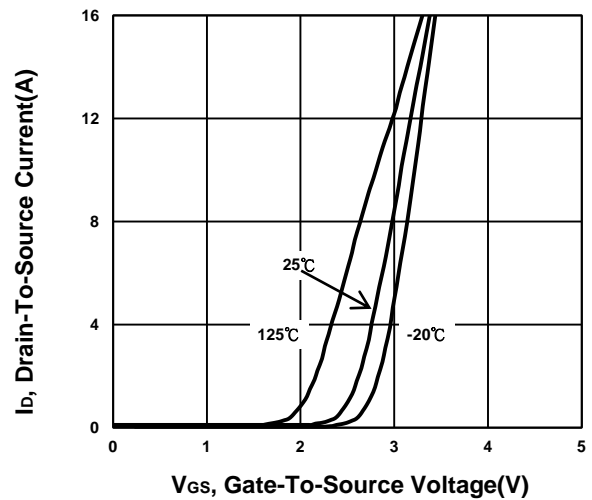
¹Pulse test : Pulse Width $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

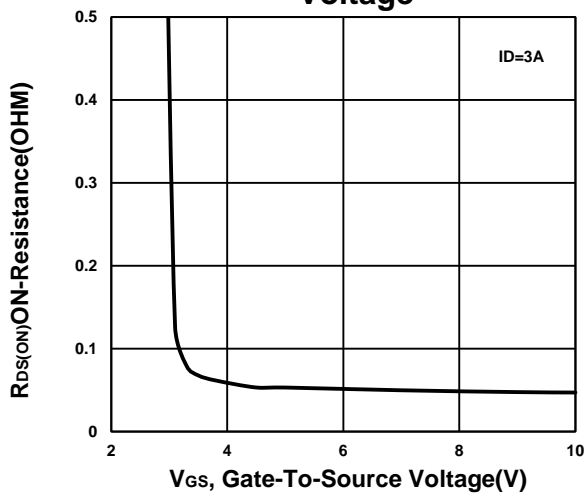
Output Characteristics



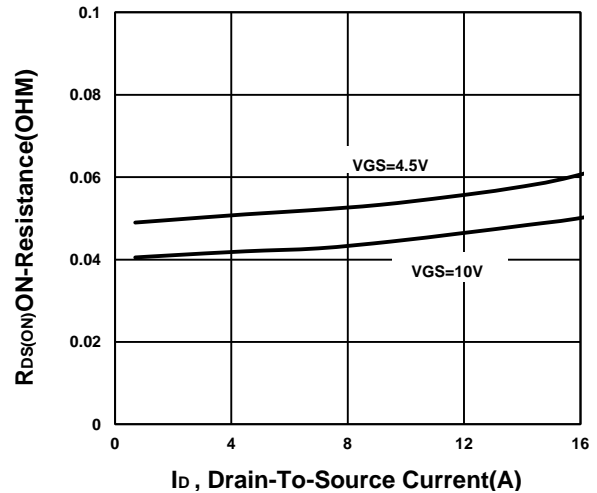
Transfer Characteristics



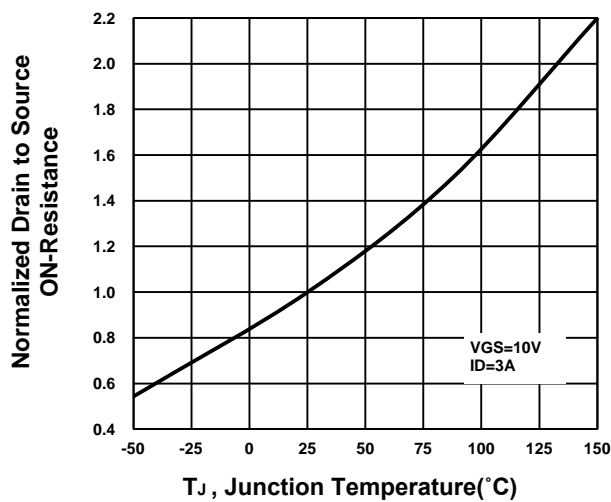
On-Resistance VS Gate-To-Source Voltage



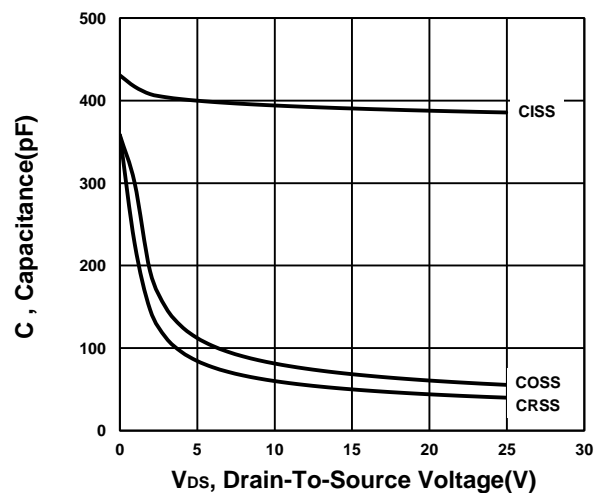
On-Resistance VS Drain Current



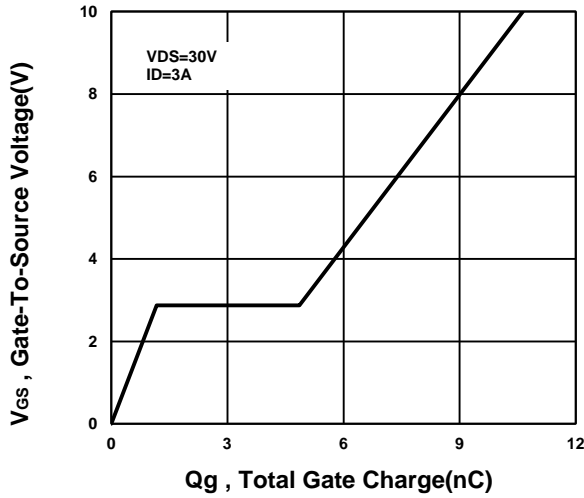
On-Resistance VS Temperature



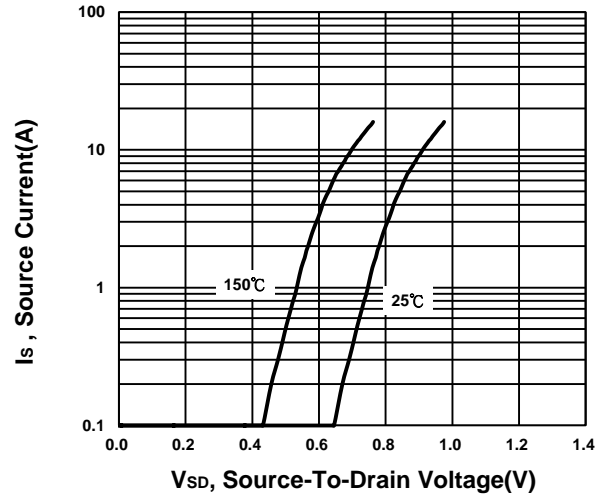
Capacitance Characteristic



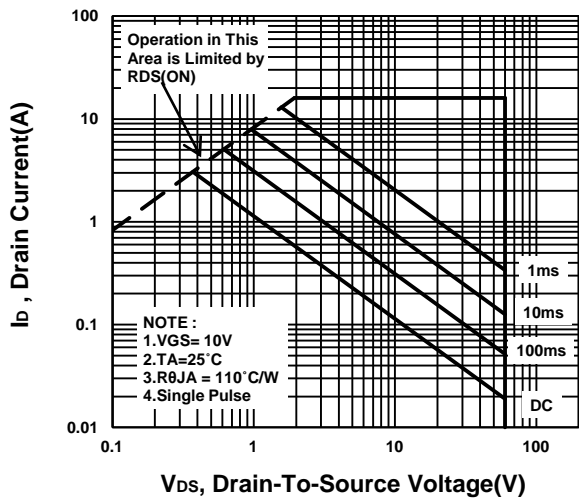
Gate charge Characteristics



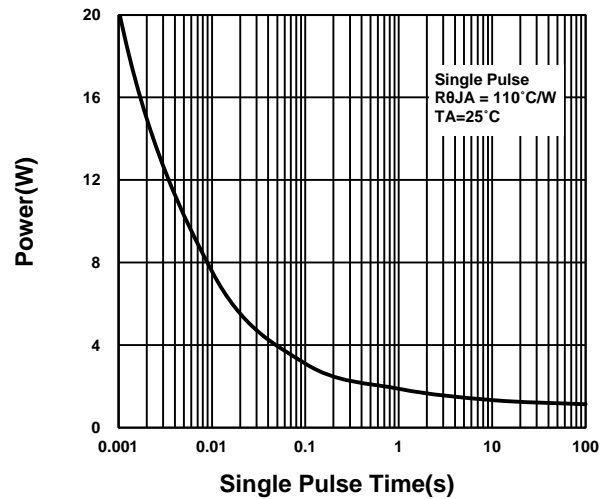
Source-Drain Diode Forward Voltage



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve

